#### Features

- Fast Read Access Time 55 ns
- Low Power CMOS Operation
  - 100 µA Maximum Standby
  - 40 mA Maximum Active at 5 MHz
- JEDEC Standard Packages
  - 40-Lead 600 mil PDIP
  - 44-Lead PLCC
  - 40-Lead VSOP (10 mm x 14 mm)
- Direct Upgrade from 512K-bit, 1M-bit, and 2M-bit (AT27C516, AT27C1024, and AT27C2048) EPROMs
- 5V ± 10% Power Supply
- High Reliability CMOS Technology - 2,000V ESD Protection
  - 200 mA Latchup Immunity
- Rapid<sup>™</sup> Programming Algorithm 50 µs/word (typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

### Description

The AT27C4096 is a low-power, high-performance 4,194,304-bit one-time programmable read only memory (OTP EPROM) organized 256K by 16 bits. It requires a single 5V power supply in normal read mode operation. Any word can be accessed in *(continued)* 

# **Pin Configurations**

Pin Name	Function
A0 - A17	Addresses
O0 - O15	Outputs
CE	Chip Enable
ŌE	Output Enable
NC	No Connect

Note: Both GND pins must be connected.

#### PDIP Top View

. –			
	$\square$		
VPP 🗆	1	40	⊐ vcc
CE 🗆	2	39	🗆 A17
015 🗆	3	38	🗆 A16
014 🗆	4	37	🗆 A15
013 🗆	5	36	🗆 A14
012 🗆	6	35	🗆 A13
011 🗆	7	34	🗆 A12
O10 🗆	8	33	🗆 A11
O9 🗆	9	32	🗆 A10
08 🗆	10	31	🗆 A9
GND 🗆	11	30	GND 🗆
07 🗆	12	29	🗆 A8
O6 🗆	13	28	🗆 A7
O5 🗆	14	27	🗆 A6
04 🗆	15	26	🗆 A5
O3 🗆	16	25	🗆 A4
02 🗆	17	24	🗆 A3
01 🗆	18	23	🗆 A2
O0 🗆	19	22	🗆 A1
OE 🗆	20	21	🗆 A0



PLCC Top View

] A15 ] A14

014 015 015 015 015 015 015 017 016

013



4-Megabit (256K x 16) OTP EPROM

# AT27C4096

Rev. 0311F-10/98



less than 55 ns, eliminating the need for speed-reducing WAIT states. The by-16 organization makes this part ideal for high-performance 16- and 32-bit microprocessor systems.

In read mode, the AT27C4096 typically consumes 15 mA. Standby mode supply current is typically less than 10  $\mu$ A.

The AT27C4096 is available in industry standard JEDEC-approved one-time programmable (OTP) plastic PDIP, PLCC, and VSOP packages. The device features two-line control ( $\overline{CE}$ ,  $\overline{OE}$ ) to eliminate bus contention in high-speed systems.

With high density 256K word storage capability, the AT27C4096 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's AT27C4096 has additional features that ensure high quality and efficient production use. The Rapid<sup>™</sup> Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50 µs/word. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

#### System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

#### **Block Diagram**



### **Absolute Maximum Ratings\***

Temperature Under Bias55°C to +125	°C
Storage Temperature65°C to +150	°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V	<b>/</b> (1)
Voltage on A9 with Respect to Ground2.0V to +14.0V	<b>/</b> (1)
V <sub>PP</sub> Supply Voltage with Respect to Ground2.0V to +14.0V	<b>/</b> (1)

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Maximum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V dc which may overshoot to +7.0V for pulses of less than 20 ns.

#### **Operating Modes**

Mode/Pin	CE	OE	Ai	V <sub>PP</sub>	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	Ai	X <sup>(1)</sup>	D <sub>OUT</sub>
Output Disable	Х	V <sub>IH</sub>	Х	Х	High Z
Standby	V <sub>IH</sub>	Х	Х	X <sup>(5)</sup>	High Z
Rapid Program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>	D <sub>IN</sub>
PGM Verify	V <sub>IH</sub>	V <sub>IL</sub>	Ai	V <sub>PP</sub>	D <sub>OUT</sub>
PGM Inhibit	V <sub>IH</sub>	V <sub>IH</sub>	х	V <sub>PP</sub>	High Z
Product Identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A17 = V_{IL}$	V <sub>cc</sub>	Identification Code

Notes: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

2. Refer to the Programming characteristics.

3.  $V_{\rm H} = 12.0 \pm 0.5$ V.

- Two identifier words may be selected. All Ai inputs are held low (V<sub>IL</sub>), except A9, which is set to V<sub>H</sub>, and A0, which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification word and high (V<sub>IH</sub>) to select the Device Code word.
- 5. Standby  $V_{CC}$  current ( $I_{SB}$ ) is specified with  $V_{PP} = V_{CC}$ .  $V_{CC} > V_{PP}$  will cause a slight increase in  $I_{SB}$ .



# <u>AÎMEL</u>

### DC and AC Operating Conditions for Read Operation

				AT27C4096		
		-55	-70	-90	-12	-15
Operating	Com.	0°C - 70°C				
Temperature (Case)	Ind.	-40°C - 85°C				
V <sub>CC</sub> Power Supply		5V ± 10%				

### **DC and Operating Characteristics for Read Operation**

Symbol	Parameter Condition		Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		± 1	μA
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		± 5	μΑ
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> Read/Standby Current	$V_{PP} = V_{CC}$		10	μΑ
1	)/ <sup>(1)</sup> Standby Current	$\frac{I_{SB1}}{CE} (CMOS)$ $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> Standby Current	$I_{SB2}$ (TTL) $\overline{CE}$ = 2.0 to V <sub>CC</sub> + 0.5V		1	mA
I <sub>cc</sub>	V <sub>CC</sub> Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$		40	mA
V <sub>IL</sub>	Input Low Voltage		-0.6	0.8	V
V <sub>IH</sub>	Input High Voltage		2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ 

2. V<sub>PP</sub> may be connected directly to V<sub>CC</sub>, except during programming. The supply current would then be the sum of I<sub>CC</sub> and I<sub>PP</sub>

# AC Characteristics for Read Operation

				AT27C4096									
				55	-7	70	-90		-*	-12 -		15	
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Units
t <sub>ACC</sub> <sup>(3)</sup>	Address to Output Delay	$\overline{CE} = \overline{OE} \\ = V_{IL}$		55		70		90		120		150	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to Output Delay	$\overline{OE} = V_{IL}$		55		70		90		120		150	ns
t <sub>OE</sub> <sup>(2)(3)</sup>	OE to Output Delay	$\overline{CE} = V_{IL}$		20		30		35		40		50	ns
t <sub>DF</sub> <sup>(4)(5)</sup>	OE or CE High to Output Float, whichever occurred first			20		20		20		30		35	ns
t <sub>OH</sub> <sup>(4)</sup>	Output Hold from Address, $\overline{CE}$ or $\overline{OE}$ , whichever occurred first		7		7		0		0		0		ns

Note: 2, 3, 4, 5. See the AC Waveforms for Read Operation diagram.

### AC Waveforms for Read Operation<sup>(1)</sup>



Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

- 2.  $\overline{OE}$  may be delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of  $\overline{CE}$  without impact on t<sub>CE</sub>.
- 3.  $\overline{OE}$  may be delayed up to  $t_{ACC}$   $t_{OE}$  after the address is valid without impact on  $t_{ACC}$ .
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

#### Input Test Waveforms and Measurement Levels

For -55 devices only:



### **Output Test Load**



Note: CL = 100 pF including jig capacitance, except for the -45 and -55 devices, where CL = 30 pF.

For -70, -90, -12 and -15 devices:

 $t_R$ ,  $t_F < 5$  ns (10% to 90%)



 $t_R$ ,  $t_F$  < 20 ns (10% to 90%)

### **Pin Capacitance**

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Max	Units	Conditions
C <sub>IN</sub>	4	10	pF	$V_{IN} = 0V$
C <sub>OUT</sub>	8	12	pF	V <sub>OUT</sub> = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.





## **Programming Waveforms**<sup>(1)</sup>



- Notes: 1. The Input Timing Reference is 0.8V for  $\rm V_{IL}$  and 2.0V for  $\rm V_{IH}.$ 
  - 2.  $t_{OE}$  and  $t_{DFP}$  are characteristics of the device but must be accommodated by the programmer.
  - When programming the AT27C4096, a 0.1 μF capacitor is required across V<sub>PP</sub> and ground to suppress spurious voltage transients.

#### **DC Programming Characteristics**

 $T_{A} = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25V, \, V_{PP} = 13.0 \pm 0.25V$ 

				Limits			
Symbol	Parameter	Test Conditions	Min	Max	Units		
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA		
V <sub>IL</sub>	Input Low Level		-0.6	0.8	V		
V <sub>IH</sub>	Input High Level		2.0	V <sub>CC</sub> + 0.7	V		
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V		
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V		
I <sub>CC2</sub>	V <sub>CC</sub> Supply Current (Program and Verify)			50	mA		
I <sub>PP2</sub>	V <sub>PP</sub> Supply Current	$\overline{CE} = V_{IL}$		30	mA		
V <sub>ID</sub>	A9 Product Identification Voltage		11.5	12.5	V		

AT27C4096

## **AC Programming Characteristics**

 $T_{\text{A}} = 25 \pm ~5^{\circ}\text{C}, ~V_{\text{CC}} = 6.5 ~\pm ~0.25\text{V}, ~V_{\text{PP}} = 13.0 \pm 0.25\text{V}$ 

			Lin			
Symbol	Parameter	Test Conditions <sup>(1)</sup>	Min Max		Units	
t <sub>AS</sub>	Address Setup Time		2		μs	
t <sub>OES</sub>	OE Setup Time		2		μs	
t <sub>DS</sub>	Data Setup Time	Input Rise and Fall Times : (10% to 90%) 20 ns	2		μs	
t <sub>AH</sub>	Address Hold Time		0		μs	
t <sub>DH</sub>	Data Hold Time	Input Pulse Levels:	2		μs	
t <sub>DFP</sub>	OE High to Output Float Delay <sup>(2)</sup>	0.45V to 2.4V	0	130	ns	
t <sub>VPS</sub>	V <sub>PP</sub> Setup Time	Input Timing Reference Level:	2		μs	
t <sub>VCS</sub>	V <sub>CC</sub> Setup Time	0.8V to 2.0V	2		μs	
t <sub>PW</sub>	CE Program Pulse Width <sup>(3)</sup>	Output Timing Reference Level:	47.5	52.5	μs	
t <sub>OE</sub>	Data Valid from $\overline{OE}$	0.8V to 2.0V		150	ns	
t <sub>PRT</sub>	V <sub>PP</sub> Pulse Rise Time During Programming		50		ns	

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ 

 This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven —see timing diagram.

3. Program Pulse width tolerance is 50  $\mu sec \pm 5\%.$ 

#### Atmel's 27C4096 Intergrated Product Identification Code

		Pins									
Codes	A0	015-08	07	<b>O</b> 6	05	04	03	02	01	00	Hex Data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device Type	1	0	1	1	1	1	0	1	0	0	00F4





### **Rapid Programming Algorithm**

A 50  $\mu$ s  $\overline{CE}$  pulse width is used to program. The address is set to the first location. V<sub>CC</sub> is raised to 6.5V and V<sub>PP</sub> is raised to 13.0V. Each address is first programmed with one 50  $\mu$ s  $\overline{CE}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50  $\mu$ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked.  $V_{PP}$  is then lowered to 5.0V and  $V_{CC}$  to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.



AT27C4096



# **Ordering Information**

I <sub>CC</sub> (mA)		; (mA)			
t <sub>ACC</sub> (ns)	Active	Standby	Ordering Code	Package	<b>Operation Range</b>
55	40	0.1	AT27C4096-55JC	44J	Commercial
			AT27C4096-55PC	40P6	(0°C to 70°C)
			AT27C4096-55VC	40V	
	40	0.1	AT27C4096-55JI	44J	Industrial
			AT27C4096-55PI	40P6	(-40°C to 85°C)
			AT27C4096-55VI	40V	
70	40	0.1	AT27C4096-70JC	44J	Commercial
			AT27C4096-70PC	40P6	(0°C to 70°C)
			AT27C4096-70VC	40V	
	40	0.1	AT27C4096-70JI	44J	Industrial
			AT27C4096-70PI	40P6	(-40°C to 85°C)
			AT27C4096-70VI	40V	
90	40	0.1	AT27C4096-90JC	44J	Commercial
			AT27C4096-90PC	40P6	(0°C to 70°C)
			AT27C4096-90VC	40V	
	40	0.1	AT27C4096-90JI	44J	Industrial
			AT27C4096-90PI	40P6	(-40°C to 85°C)
			AT27C4096-90VI	40V	
120	40	0.1	AT27C4096-12JC	44J	Commercial
			AT27C4096-12PC	40P6	(0°C to 70°C)
			AT27C4096-12VC	40V	
	40	0.1	AT27C4096-12JI	44J	Industrial
			AT27C4096-12PI	40P6	(-40°C to 85°C)
			AT27C4096-12VI	40V	
150	40	0.1	AT27C4096-15JC	44J	Commercial
			AT27C4096-15PC	40P6	(0°C to 70°C)
			AT27C4096-15VC	40V	
	40	0.1	AT27C4096-15JI	44J	Industrial
			AT27C4096-15PI	40P6	(-40°C to 85°C)
			AT27C4096-15VI	40V	

Package Type	
44J	44-Lead, Plastic J-Leaded Chip Carrier (PLCC)
40P6	40-Lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)
40V	40-Lead, Plastic Thin Small Outline Package (VSOP) 10 x 14 mm





### **Packaging Information**



# AT27C4096





#### **Atmel Headquarters**

#### Corporate Headquarters 2325 Orchard Parkway San Jose, CA 95131

TEL (408) 441-0311 FAX (408) 487-2600

#### Europe

Atmel U.K., Ltd. Coliseum Business Centre Riverside Way Camberley, Surrey GU15 3YL England TEL (44) 1276-686677 FAX (44) 1276-686697

#### Asia

Atmel Asia, Ltd. Room 1219 Chinachem Golden Plaza 77 Mody Road Tsimshatsui East Kowloon, Hong Kong TEL (852) 27219778 FAX (852) 27221369

#### Japan

Atmel Japan K.K. Tonetsu Shinkawa Bldg., 9F 1-24-8 Shinkawa Chuo-ku, Tokyo 104-0033 Japan TEL (81) 3-3523-3551 FAX (81) 3-3523-7581

#### **Atmel Operations**

#### Atmel Colorado Springs

1150 E. Cheyenne Mtn. Blvd. Colorado Springs, CO 80906 TEL (719) 576-3300 FAX (719) 540-1759

#### Atmel Rousset

Zone Industrielle 13106 Rousset Cedex, France TEL (33) 4 42 53 60 00 FAX (33) 4 42 53 60 01

#### Fax-on-Demand

North America: 1-(800) 292-8635 International: 1-(408) 441-0732

*e-mail* literature@atmel.com

*Web Site* http://www.atmel.com

**BBS** 1-(408) 436-4309

#### © Atmel Corporation 1998.

Atmel Corporation makes no warranty for the use of its products, other than those expressly contained in the Company's standard warranty which is detailed in Atmel's Terms and Conditions located on the Company's website. The Company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice, and does not make any commitment to update the information contained herein. No licenses to patents or other intellectual property of Atmel are granted by the Company in connection with the sale of Atmel products, expressly or by implication. Atmel's products are not authorized for use as critical components in life support devices or systems.

Marks bearing <sup>®</sup> and/or <sup>™</sup> are registered trademarks and trademarks of Atmel Corporation.

Terms and product names in this document may be trademarks of others.

